

Nove pobude za delo v IEC – SEPTEMBER 2026

Referenčna oznaka	Naslov	Tehnični odbor	Odbor (SIST)
106/757/NP	PNW 106-757 ED1: Measurement of specific absorption rate – Human exposure to radio frequency electromagnetic fields from hand-held and body-worn wireless communication devices (Frequency range of 4 MHz to 10 GHz) – Part 102: Measuring System Requirements	TC 106	NI AKTIVNO PODROČJE
110/1895/NP	PNW 110-1895 ED1: International Electrotechnical Vocabulary (IEV) - Part xxx-02: Electronic technologies and systems - Fundamental concepts of Virtual, Augmented and Mixed Realities	TC 110	NI AKTIVNO PODROČJE
113/1002/NP	PNW 113-1002 ED1: Nanomanufacturing - Key control characteristics – Part 11-7: Shielding effectiveness of nano-composites based on dielectric nanoparticles: Free-space method	TC 113	NI AKTIVNO PODROČJE
124/403/NP	PNW 124-403 ED1: Wearable electronic devices and technologies - Part 202-2: Test method for e-textile antenna under stretch-induced deformation	TC 124	NI AKTIVNO PODROČJE
124/405/NP	PNW 124-405 ED1: Wearable electronic devices and technologies - Part 201-5: Electronic textile - Cut-out measurement method of sheet resistance of conductive fabric by planer electrode and straight-line electrode	TC 124	NI AKTIVNO PODROČJE
2/2327/NP	PNW 2-2327 ED1: Rotating electrical machines – Part 2-4: Specific test methods for determining losses and efficiency of servo motors	TC 2	SIST/TC ERS
21/1322/NP	PNW 21-1322 ED1: Battery data and semantic interoperability	TC 21	NI AKTIVNO PODROČJE
23K/142/NP	PNW 23K-142 ED1: Energy Efficiency - Customer Energy Management Systems – 4-1: General requirements for switching devices intended for prosumer electrical installation (PEI) and similar uses	SC 23K	SIST/TC ELI
45A/1671/NP	PNW TS 45A-1671 ED1: Nuclear Facilities – Instrumentation, Control and Electrical Power Systems – Explainability Aspects of Artificial Intelligence Applications	SC 45A	NI AKTIVNO PODROČJE
47/3048/NP	PNW 47-3048 ED1: Semiconductor devices - Performance evaluation of semiconductor processing components and inspection equipment - Part 2: Nano-scale wafer surface inspection method using white light interferometry	TC 47	NI AKTIVNO PODROČJE
47E/909/NP	PNW 47E-909 ED1: Semiconductor devices - Test method of pH sensors for metabolic status assessment of cultured cells	SC 47E	NI AKTIVNO PODROČJE
48D/814/NP	PNW 48D-814 ED1: Mechanical structures for electrical and electronic equipment – Walk-in enclosures – Part 1: Design guidelines	SC 48D	NI AKTIVNO PODROČJE

59F/594/NP	PNW 59F-594 ED1: Surface cleaning appliances - Part 17: Window cleaning robots for household or similar use - Methods for measuring the performance	SC 59F	SIST/TC FGA
65A/1260/NP	PNW 65A-1260 ED1: Batch control - Part 5: Procedure Function Charts	SC 65A	SIST/TC MOV
81/822/NP	PNW TS 81-822 ED1: Inspection of lightning protection system (LPS) and surge protection measures (SPM) of buildings/structures	TC 81	SIST/TC STZ
86C/2041/NP	PNW 86C-2041 ED1: Optical amplifiers – Test methods – Part 10-6: Four wave mixing crosstalk	SC 86C	SIST/TC MOC
91/2142/NP	PNW 91-2142 ED1: Circuit board assemblies - Part 8: Voiding in solder joints - Best practices	TC 91	NI AKTIVNO PODROČJE
JTC1-SC41/644/NP	PNW JTC1-SC41-644 ED1: Internet of things (IoT) - General requirements and use cases of information publishing systems based on IoT	ISO/IEC JTC 1/SC 41	NI AKTIVNO PODROČJE